



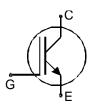
IGBT³ Chip

SIGC12T120

FEATURES:

- 1200V Trench & Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

- This chip is used for:
- power module
- **Applications:**
- drives



Chip Type	V _{CE}	V _{CE} I _{Cn} Die Size		Package	Ordering Code	
SIGC12T120	1200V	8A	3.54 x 3.5 mm ²	sawn on foil	Q67050- A4102-A001	

MECHANICAL PARAMETER:

Raster size	3.54 x 3.5	mm	
Emitter pad size	2.028 x 2.028		
Gate pad size	1.107 x 0.702		
Area total / active	12.4 / 6.9	mm ²	
Thickness	140	μm	
Wafer size	150	mm	
Flat position	0	grd	
Max.possible chips per wafer	1200 pcs		
Passivation frontside	Photoimide		
Emitter metallization	3200 nm AlSiCu		
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm		
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C		



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	24	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C = 0.5mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =8A	1.4	1.7	2.1	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_C{=}300\mu A$, $V_{GE}{=}V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =1200V , V_{GE} =0V			50	μA
Gate-emitter leakage current	I _{GES}	$V_{CE}=0V$, $V_{GE}=20V$			120	nA
Integrated gate resistor	R _{Gint}					Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol Conditions	Value			Unit	
Falameter	Symbol	Conditions	min.	typ.	max.	Omt
Input capacitance	Ciss	V _{CE} =25V,		605		pF
Output capacitance	Coss	$V_{GE}=0V$,		37		
Reverse transfer capacitance	Crss	f=1MHz		29		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load

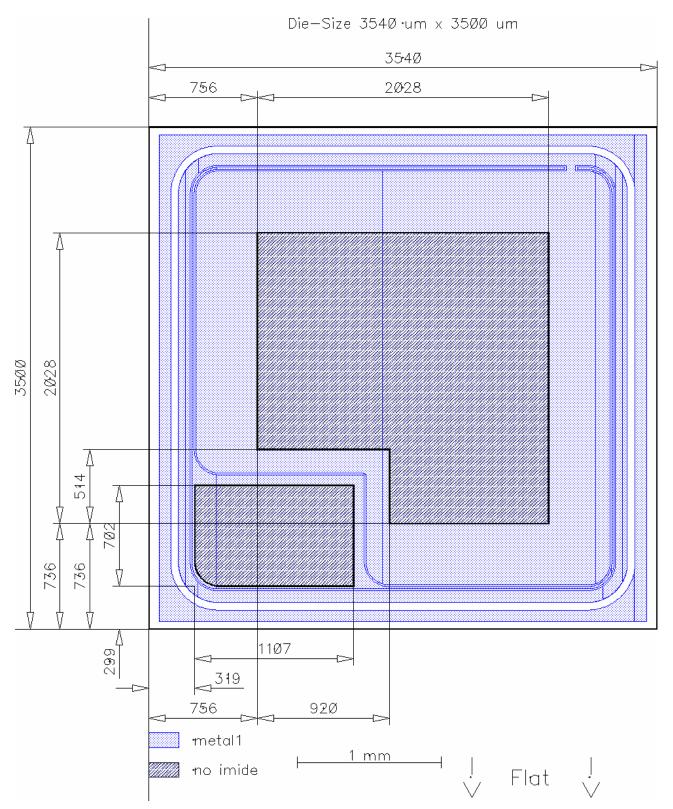
Parameter	Symbol	Conditions ¹⁾	Value			Unit
			min.	typ.	max.	
Turn-on delay time	t _{d(on)}	<i>T</i> _j =125°C		tbd		ns
Rise time	<i>t</i> r	V _{CC} =600V, I _C =25A, V _{GE} =-15/15V,		tbd		
Turn-off delay time	$t_{d(off)}$	V _{GE} =-15/15V,		tbd		
Fall time	t _f	$R_{\rm G}$ = Ω		tbd		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



SIGC12T120

CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the	tbd	
device data sheet		

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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